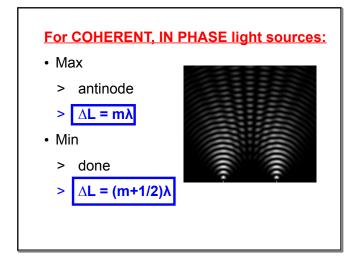
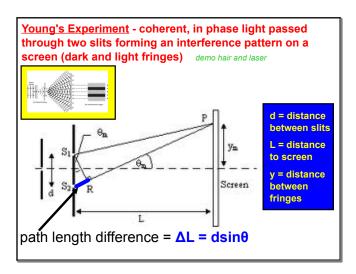
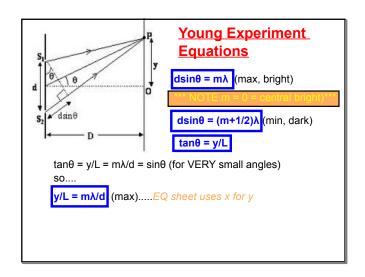


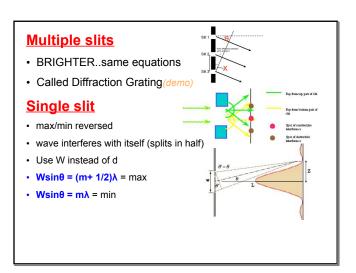
Wave Review

- <u>Superposition</u> = addition of mulitple wave amplitudes
- constructive interference = two crests or two troughs combine = BRIGHT = MAX
- <u>destructive interference</u> = crest and trough combine = DARK = MIN



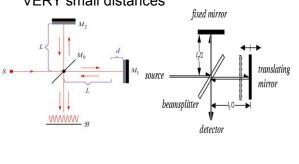


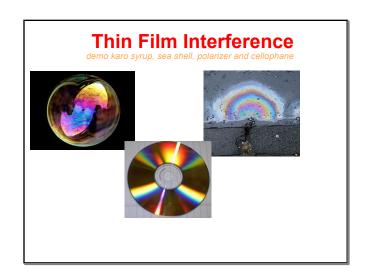




Interferometer

 Device using light interference to measure VERY small distances

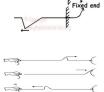


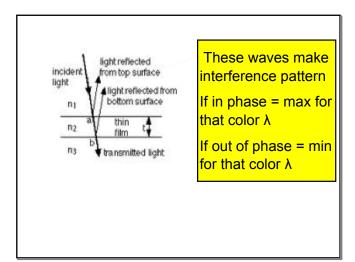


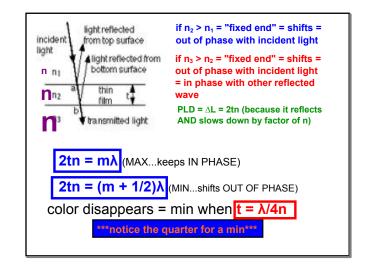
Thin Film Interference

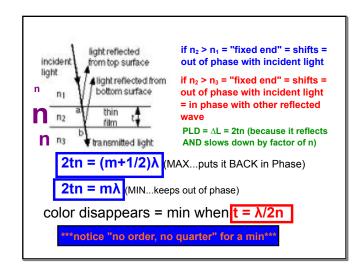
- · Due to different n's in different media
- Dependent on
 - > n
 - > angle
 - > arigie
 - > reflection from different surfaces

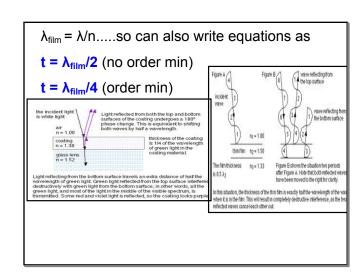
- If reflects off <u>BIGGER</u>
 n = fixed = <u>shifts</u>
 wave from crest to
 trough
- If reflects off <u>smaller</u>
 n = free = no shift











Used to determine thickness between atoms in layered crystal lattice Like thin film, light refects off atoms mλ = 2d sin θ nλ = 2d sin θ as applied to X-ray Diffraction techniques nλ = 2d sin θ as the angle of incidence = the angle of reflection